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Pre Amdt
S Davis
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PATENT
0465-0879P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicants: Ha Zoong KIM Conf.: Unassigned
Appl. No.: NEW Group: Unassigned
Filed: November 29, 2001 Examiner: Unassigned
For: DDB TEST PATTERN AND METHOD FOR TESTING TDDB OF
MOS CAPACITOR DIELECTRIC

PRELIMINARY AMENDMENT

Assistant Commissioner for Patents
Washington, D.C. 20231

November 29, 2001

Sir:

Prior to initial examination of this divisional application, please amend the
above-identified application as follows:

IN THE CLAIMS

**Please cancel claims 1-10 without prejudice or disclaimer of the
subject matter contained therein.**

Please add the following additional claims:

--13. (New) A unit test cell of a Time Dependent Dielectric Breakdown
(TDDB) test pattern circuit, comprising:

a MOS capacitor with a first electrode connected to ground;

a MOS transistor with a source electrode connected to the first electrode of

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